

The 128Mb SDRAM is a high-speed CMOS, dynamic random-access memory containing 134,217,728 bits. Each is internally configured as a quad-bank DRAM. Read and write accesses to the SDRAM are burst oriented; accesses start at a selected location and continue for a programmed number of locations in a programmed sequence. Accesses begin with the registration of an ACTIVE command, which is then followed by a READ or WRITE command. The address bits registered coincident with the ACTIVE command are used to select the bank and row to be accessed (BA0, BA1 select the bank; A0-A11 select the row). The address bits registered



128Mb: x4, x8, x16 SDRAM 3.3V

coincident with the READ or WRITE commands are used to select the starting column location for the burst access.

The SDRAM provides for programmable READ or WRITE burst lengths of 1, 2, or 4 locations with burst terminate option using the Burst Interleaved Addressing mode only. An AUTO PRECHARGE function may be enabled to provide a self-timed row precharge that is initiated at the end of the burst sequence.

The 128Mb SDRAM uses an internal pipelined architecture to achieve high-speed operation. This architecture is compatible with the 2n rule of prefetch architectures, but it also allows the column address to be changed on every clock cycle to achieve a high-speed, fully random access. Precharging one bank while accessing one of the other three banks will hide the precharge cycles and provide seamless high-speed, random-access operation.

The 128Mb SDRAM is designed to operate in 3.3V, low-power memory systems. An auto refresh mode is provided, along with a power-saving power-down mode. All inputs and outputs are LVTTTL-compatible. SDRAMs offer substantial advances in DRAM operating performance, including the abilities to synchronously burst data at a high data rate with automatic column-address generation, to interleave between internal banks in order to hide precharge time, and to randomly change column addresses on each clock cycle during a burst access.

The x8 devices are optimized for single bank DIMM applications. The x16 devices are available for both single and dual bank DIMM applications.

Disclaimer:

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ABSOLUTE MAXIMUM RATINGS:

Voltage on Vdd Supply relative to Vss	-1 to +4.6V
Operating Temperature T _A (Ambient)	25° to +70 °C
Storage Temperature	-55 to +150 °C
Power Dissipation	1 W
Short Circuit Output Current	50 mA

Stresses beyond these may cause permanent damage to the device. This is a stress rating only and functional operation of the device at or beyond these conditions is not implied. Exposure to these conditions for extended periods may affect reliability.

CAPACITANCE:

Parameter	Symbol	Min	Max	Units
Input Capacitance: A0 - A11, BA0, BA1	C _{in}	1	5	pF
Input Capacitance: RAS#, CAS#, WE#, DQM, CLK, CKE, CS#	C _{in}	1	5	pF
Input/Output Capacitance: DQs	C _{io}	1	6	pF

DC ELECTRICAL CHARACTERISTICS AND RECOMMENDED OPERATING CONDITIONS:

Parameter	Symbol	Min	Max	Units
Supply Voltage	V _{dd} /V _{ddq}	3.0	3.6	V
Input High (Logic 1) Voltage, All inputs	V _{ih}	2.2	V _{dd} + 3	V
Input Low (Logic 0) Voltage, All inputs	V _{il}	-0.3	0.8	V
Input Leakage Current Any input = 0V ≤ V _{IN} ≤ V _{dd} All other pins not under test = 0V	I _i	-10	10	μA
Output Leakage Current DQs are disabled; 0V ≤ V _{OUT} ≤ V _{ddq}	I _{oq}	-10	10	μA
Output High Voltage (I _{OUT} = -4 mA)	V _{oh}	2.4		V
Output Low Voltage (I _{OUT} = 4 mA)	V _{ol}		0.4	V

ICC OPERATING CONDITIONS AND MAXIMUM LIMITS: Vdd = 3.3V ± 10%V, Temp. = 25° to 70 °C

Supply Current		Symbol	-75A	-8A	Units	Notes
OPERATING CURRENT: ACTIVE mode, burst = 1, READ or WRITE, tRC ≥ tRC (MIN), one bank active, CL=3		Icc1	165	140	mA	1, 2, 3, 4
STANDBY CURRENT: POWER-DOWN mode, CKE = LOW, no accesses in progress	Standard parts	Idd2	9	9	mA	32
	Self refresh parts	Idd2	3	3	mA	32
STANDBY CURRENT: CS# = HIGH, CKE = HIGH, all banks idle		Icc3	75	60	mA	1, 2, 3, 4
STANDBY CURRENT: CS# = HIGH, CKE = HIGH, all banks active after tRCD met, no accesses in progress.		Icc4	75	50	mA	1, 2, 3, 4
OPERATING CURRENT: BURST mode after tRCD met, continuous burst, READ, WRITE, all banks active, CL=3		Icc5	165	145	mA	1, 2, 3, 4
AUTO REFRESH CURRENT tRC ≥ tRC (MIN) CL = 3		Icc6	265	245	mA	1, 2, 3, 4
AUTO REFRESH CURRENT tRC=15.6us CL = 3		Icc7	50	50	mA	1, 2, 3, 4
SELF REFRESH CURRENT (Self refresh parts only, part M)		Idd8	3	3	mA	

Notes

1. All voltages referenced to Vss.
2. An initial pause of 100 μs is required after power-up, followed by two AUTO REFRESH commands, before proper device operation is ensure. (Vdd and VddQ must be powered-up simultaneously Vss and VssQ must be at the same potential.) The two AUTO REFRESH command wake-ups should be repeated any time the 'REF refresh requirement is exceeded.
3. Icc specifications are tested after the device is properly initialized. tCK= 10ns for -8 and tCK=7.5ns for -75A.

AC ELECTRICAL CHARACTERISTICS: Vdd = 3.3V ± 10%V, Temp. = 25° to 70°C

AC CHARACTERISTICS		-75A	-75A	-8A	-8A		
PARAMETER	SYMBOL	MIN	MAX	MIN	MAX	UNITS	NOTES
Access time from CLK (positive edge) CL = 3	tAC		5.4		6	ns	
Access time from CLK (positive edge) CL = 2	tAC		N/A			ns	
Address hold time	tAH	0.8		1		ns	
Address setup time	tAS	1.5		2		ns	
CLK high level width	tCH	2.5		3		ns	
CLK low level width	tCL	2.5		3		ns	
Clock cycle time CL = 3	tCK	7.5		10		ns	
Clock cycle time CL = 2	tCK	N/A				ns	
CKE hold time	tCKH	0.8		1		ns	
CKE setup time	tCKS	1.5		2		ns	
CS#, RAS#, CAS#, WE#, DQM hold time	tCMH	0.8		1		ns	
CS#, RAS#, CAS#, WE#, DQM setup time	tCMS	1.5		2		ns	
Data-in hold time	tDH	0.8		1		ns	
Data-in setup time	tDS	1.5		2		ns	
Data-out high impedance time	tHZ		9		9	ns	4
Data-out low impedance time	tLZ	1		2		ns	
Data-out hold time	tOH	2.7		3		ns	
ACTIVE to PRECHARGE command period	tRAS	44	16K	50	16K	ns	
AUTO REFRESH to ACTIVE command period	tRC	60		80		ns	
ACTIVE to READ or WRITE delay	tRCD	22.5		30		ns	
Refresh period (4096 cycles)	tREF		64		64	ms	
PRECHARGE command period	tRP	22.5		30		ns	
ACTIVE bank A to bank B command period	tRRD	15		20		ns	
Transition time	tT	0.3	2	0.3	2	ns	
Write recovery time	tWR	20		20		ns	3
Exit SELF REFRESH to ACTIVE command	tXSR	8		8		tCK	
READ/WRITE command to READ/WRITE command	tCCD	1		1		tCK	1
CKE to clock disable or power down entry mode	tCKED	1		1		tCK	2
CKE to clock enable or power down exit setup	tPED	1		1		tCK	2

AC ELECTRICAL CHARACTERISTICS: Vdd = 3.3V ± 10%V, Temp. = 25° to 70°C

AC CHARACTERISTICS		-75A	-75A	-8	-8		
PARAMETER	SYMBOL	MIN	MAX	MIN	MAX	UNITS	NOTES
DQM to input data delay	tDQD	0		0		tCK	1
WRITE command to input data delay	tDWD	0		0		tCK	1
Data-in to ACTIVATE command w/ Auto precharge	tDAL	5		5		tCK	3
Data-in to precharge	tDPL	2		2		tCK	2, 3
Last data-in to precharge command	tRDL	2		2		tCK	1
LOAD MODE REGISTER command to command	tMRD	2		2		tCK	1
Data-out to high impedance from precharge	tROH	3		3		tCK	1

NOTES:

1. Clocks required specified by JEDEC functionality and not dependent on any timing parameter.
2. Timing actually specified by tCKS, clock(s) specified as a reference only at a minimum cycle rate.
3. Timing actually specified by tWR plus tRP clock(s) specified as a reference only at a minimum cycle rate.
4. tHZ defines the time at which the output achieves the open circuit condition; it is not a reference to Voh or Vol. The last valid data element will meet tOH before going high-Z.
5. Based on tCK = 10ns for -8 and tCK = 7.5ns for -75a

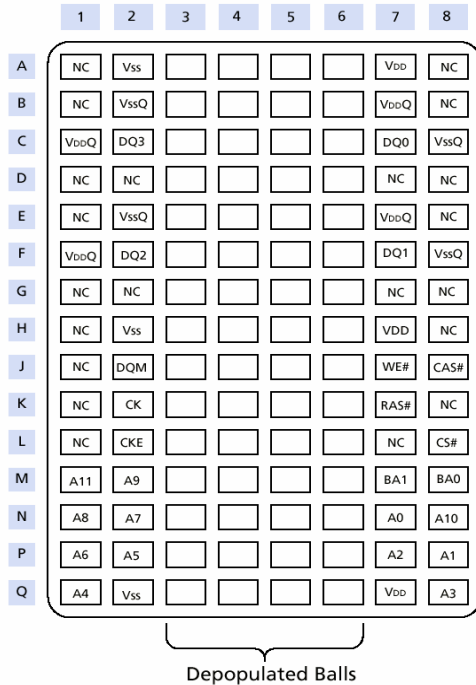
NOTE:

1. All dimensions in millimeters MAX/MIN or typical where noted.
2. Package width and length do not include mold protrusion; allowable mold protrusion is 0.25mm per side.

FBGA PIN ASSIGNMENT (Top View)

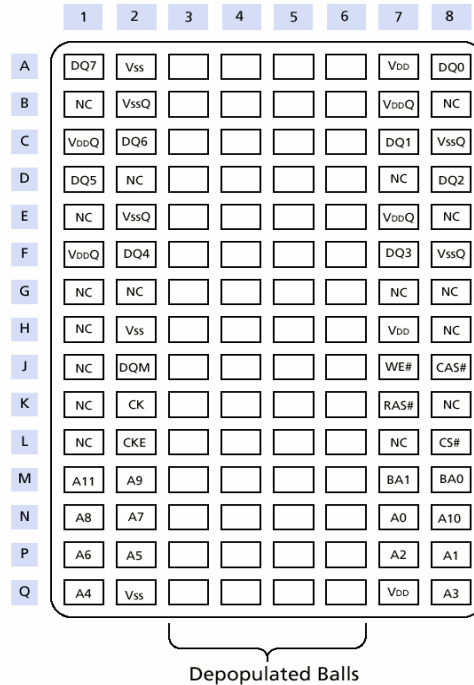
32 Meg x 4 SDRAM

11 x 13mm



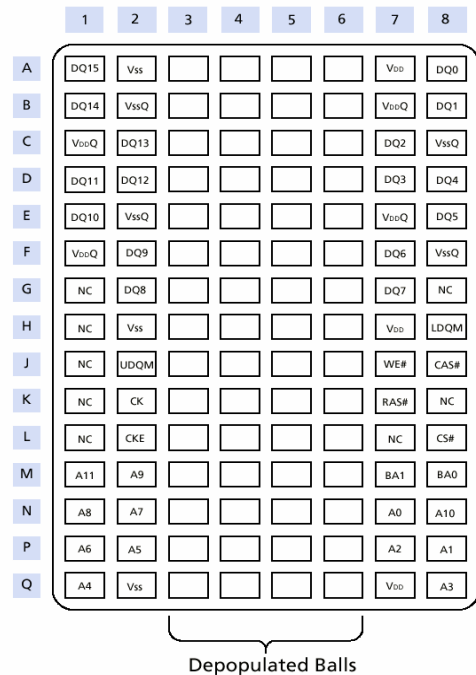
16 Meg x 8 SDRAM

11 x 13mm

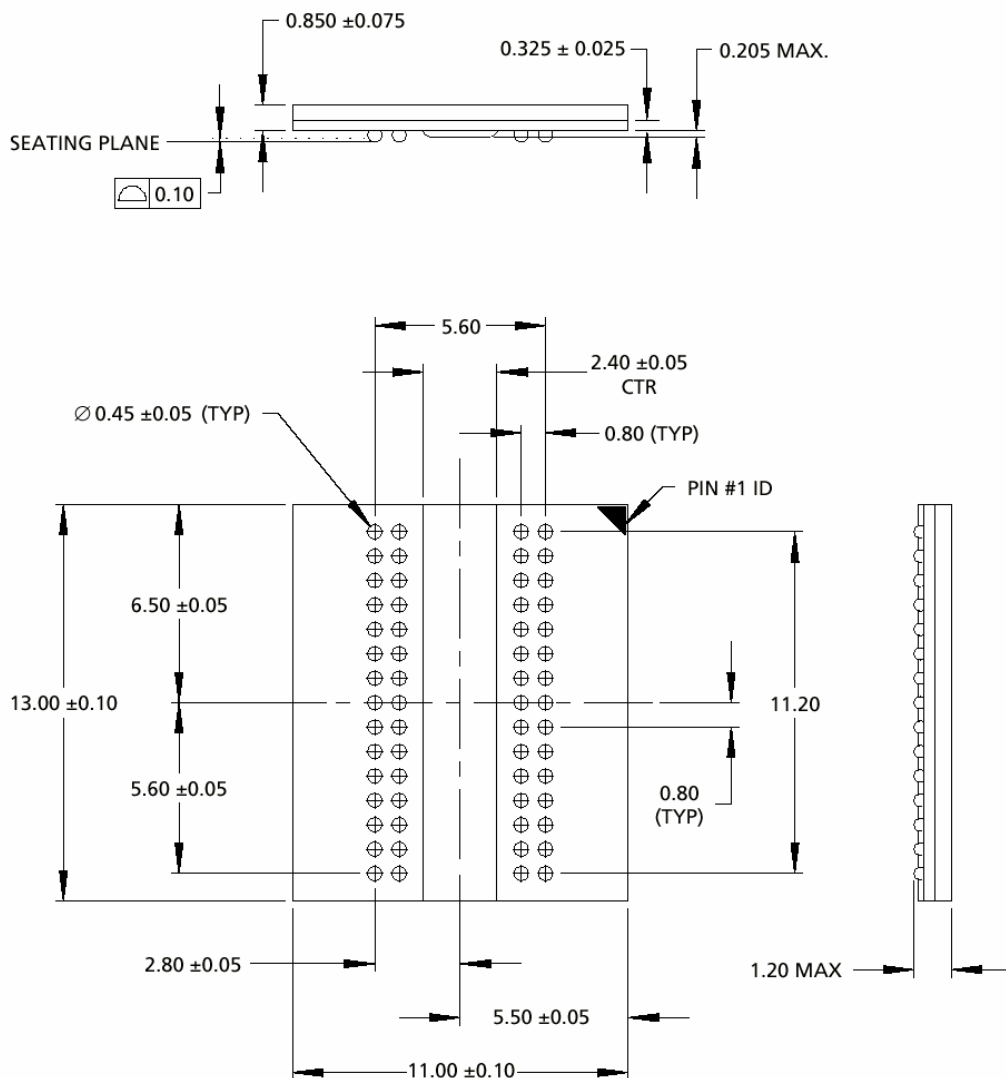


8 Meg x 16 SDRAM

11 x 13mm

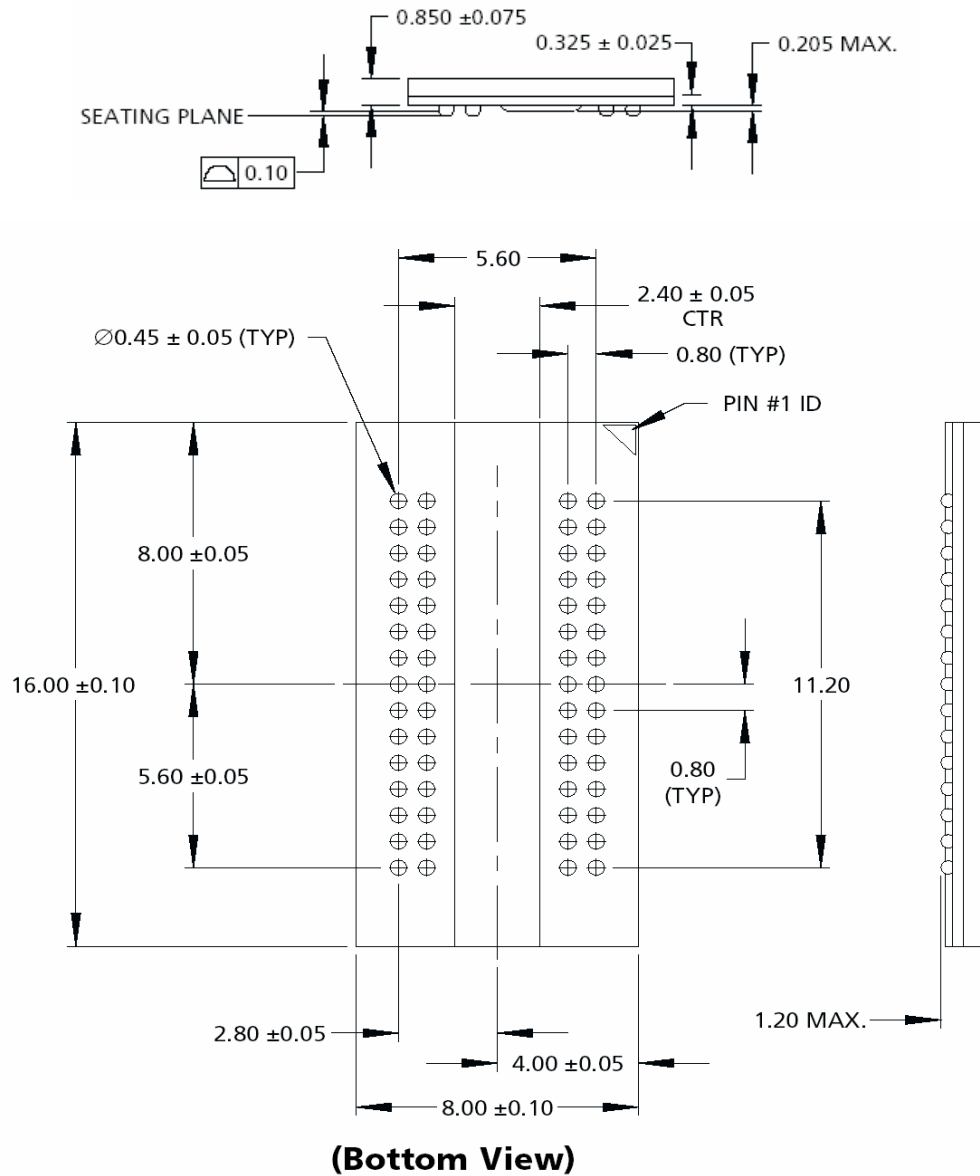


FBGA "FC" PACKAGE 60-pin, 11mm x 13mm



(Bottom View)

- NOTE:**
1. All dimensions in millimeters.
 2. Recommended Pad size for PCB is 0.33mm±0.025mm.

FBGA “FB” PACKAGE
60-pin, 8mm x 16mm


- NOTE:**
1. All dimensions in millimeters.
 2. Recommended Pad size for PCB is 0.33mm±0.025mm.

PART NUMBERS FOR PRODUCT PRIOR TO DECEMBER 2004**Options:****Marking:****Architecture:**

32 Meg x 4 (8 Meg x 4 x 4 banks)	S40032LK8
16 Meg x 8 (4 Meg x 8 x 4 banks)	S80016LK7
8 Meg x 16 (2 Meg x 16 x 4 banks)	S16008LK9

Voltage and Refresh:

3.3V, Auto Refresh	LK
3.3V, Self or Auto Refresh ¹	MK

Device Configuration:

32 Meg x 4	8
16 Meg x 8	7
8 Meg x 16	9

Package Types:

54-pin plastic TSOP (400 mil)	TW
60-ball FBGA (8mm x 16mm)	FB ²
60-ball FBGA (11mm x 13mm)	FC ²

Timing Types:

PC100 (3-3-3)	-8A
PC133 (3-3-3)	-75A

Part number example: S80016LK7TW-8A

NOTES: 1. Only when specified. Consult Sales
2. Not available in x16 configuration

http://www.spectek.com/menus/part_guides.asp